

12/03

Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 117974		APPLICATION NO. New U.S. Patent Application 10/727, 115	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Noriyoshi SAKABE			
				FILING DATE December 5, 2003			

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
	1	Noriyoshi SAKABE., "X-ray diffraction data collection system for modern protein crystallography with a Weissenberg camera and a imaging plate using synchrotron radiation", Nuclear Instruments and Methods in Physics Research A303 (1991), Pgs. 448-463
	2	K. SAKABE et al., "Large-Format Imaging Plate and Weissenberg Camera for Accurate Protein Crystallographic Data Collection Using Synchrotron Radiation", J. Synchrotron Rad. (1997), Pgs. 136-146
	3	Noriyoshi SAKABE et al., "Automatic Weissenberg data collection system for time-resolved protein crystallography", Nuclear Instruments and Methods in Physics Research A 467-468 (2001), Pgs. 1367-1371

EXAMINER	DATE CONSIDERED 1/19/06
----------	-------------------------

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: December 5, 2003

Form PTO-1449
(REV. 8-83)US Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
117974APPLICATION NO.
10/727,715

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS
Noriyoshi SAKABEFILING DATE
December 5, 2003

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>R</i>	1	4,771,174	09/13/1988	TORII		
<i>R</i>	2	4,933,558	06/12/1990	CARTER et al.		
<i>R</i>	3	5,038,037	08/06/1991	SAOTOME		
<i>R</i>	4	3,350,560	10/31/1967	PRICKETT et al.		

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
<i>R</i>	4	EP 0 125 800 A1	11/21/1984	Europe		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: June 15, 2004